

Description

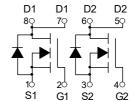
The SI4936BDY-T1-GE3 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

D1_{D1}_{D2} D2 S1_{G1}_{S2</sup>_{G2}}

SOP-8 (SOIC-8)

General Features

 $V_{DS} = 30V I_D = 6A$ $R_{DS(ON)} < 30m\Omega @ V_{GS} = 10 V$ $R_{DS(ON)} < 42m\Omega @ V_{GS} = 4.5V$



Application

Battery protection

Load switch

Uninterruptible power supply

Dual N-Channel MOSFET

Package Marking and Ordering Information

| Product ID | Pack | Brand | Qty(PCS) |
|------------------|---------------|------------|----------|
| SI4936BDY-T1-GE3 | SOP-8(SOIC-8) | HXY MOSFET | 3000 |

Absolute Maximum Ratings@T_j=25°C(unless otherwise specified)

| Symbol | Parameter | Rating | Units |
|--------------------------------------|---|-------------|-------|
| V _{DS} | Drain-Source Voltage | 30 | V |
| V _G s | Gate-Source Voltage | <u>+</u> 20 | V |
| I _D @T _A =25°C | Drain Current, V _{GS} @ 4.5V ³ | 6 | А |
| I _D @T _A =70°C | Drain Current, V _{GS} @ 4.5V ³ | 5 | А |
| Ірм | Pulsed Drain Current ¹ | 30 | А |
| P _D @T _A =25°C | Total Power Dissipation | 2 | W |
| Тѕтс | Storage Temperature Range | -55 to 150 | °C |
| TJ | Operating Junction Temperature Range | -55 to 150 | °C |
| Rthj-a | Maximum Thermal Resistance, Junction- ambient ³ | 62.5 | °C/W |

Dual N-Channel Enhancement Mode MOSFET

Electrical Characteristics (T_J =25°C unless otherwise noted)

| Symbol | Parameter | Conditions | | Min | Тур | Max | Units |
|----------------------|-------------------------------------|---|-----------------------|-----|------|------|-------|
| Static Pa | rameters | | | | | | |
| BV_{DSS} | Drain-Source Breakdown Voltage | $I_D = -250 \mu A, V_{GS} = 0 V$ | | 30 | | | V |
| | Zero Gate Voltage Drain Current | V_{DS} =30V, V_{GS} =0V | | | | 1 | μΑ |
| I _{DSS} | | T _J =55℃ | | | | 5 | μΑ |
| I_{GSS} | Gate-Body leakage current | V_{DS} =0V, V_{GS} =±20V | | | | ±100 | nA |
| $V_{GS(th)}$ | Gate Threshold Voltage | $V_{DS}=V_{GS} I_{D}=250\mu A$ | | 1.2 | 1.8 | 2.4 | V |
| $I_{D(ON)}$ | On state drain current | V_{GS} =10V, V_{DS} =5V | | 30 | | | Α |
| | Static Drain-Source On-Resistance | V_{GS} =10V, I_D =6A | | | 25 | 30 | mΩ |
| $R_{DS(ON)}$ | | | T _J =125°C | | 40 | 48 | 11122 |
| | | V_{GS} =4.5V, I_D =5A | | | 33 | 42 | mΩ |
| g _{FS} | Forward Transconductance | $V_{DS}=5V$, $I_{D}=6A$ | | | 15 | | S |
| V_{SD} | Diode Forward Voltage | I _S =1A,V _{GS} =0V | | | 0.76 | 1 | V |
| Is | Maximum Body-Diode Continuous Curre | rent | | | | 2.5 | Α |
| Dynamic | Parameters | | | | | | |
| C _{iss} | Input Capacitance | V _{GS} =0V, V _{DS} =15V, f=1MHz | | | 255 | 310 | pF |
| C _{oss} | Output Capacitance | | | | 45 | | pF |
| C _{rss} | Reverse Transfer Capacitance | | | | 35 | 50 | рF |
| R_g | Gate resistance | V _{GS} =0V, V _{DS} =0V, f=1MHz | | 1.6 | 3.25 | 4.9 | Ω |
| Switching | g Parameters | | | | | | |
| Q _{g(10V)} | Total Gate Charge | | | | 5.2 | 6.3 | nC |
| Qg _(4.5V) | | V_{GS} =10V, V_{DS} =15V, I_{D} =6A | | | 2.55 | 3.2 | nC |
| Q_{gs} | Gate Source Charge | | | | 0.85 | | nC |
| Q_{gd} | Gate Drain Charge | | | | 1.3 | | nC |
| t _{D(on)} | Turn-On DelayTime | | | | 4.5 | | ns |
| t _r | Turn-On Rise Time | V_{GS} =10V, V_{DS} =15V, R_L =2.5 Ω , R_{GEN} =3 Ω | | | 2.5 | | ns |
| t _{D(off)} | Turn-Off DelayTime | | | | 14.5 | | ns |
| t _f | Turn-Off Fall Time | | | | 3.5 | | ns |
| t _{rr} | Body Diode Reverse Recovery Time | I _F =6A, dI/dt=100A/μs | | | 8.5 | | ns |
| Q _{rr} | Body Diode Reverse Recovery Charge | I _F =6A, dI/dt=100A/μs | | | 2.2 | | nC |

A. The value of $R_{\theta JA}$ is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with T_A =25°C. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(MAX)}$ =150°C, using \leq 10s junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}$ =150°C. Ratings are based on low frequency and duty cycles to keep initial T_{J} =25°C.

D. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to lead $R_{\theta JL}$ and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedence which is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(MAX)}$ =150°C. The SOA curve provides a single pulse ratin g.



Typical Electrical And Thermal Characteristics

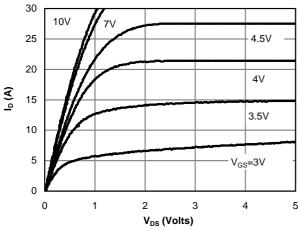
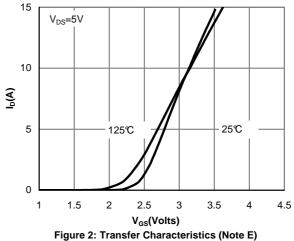


Fig 1: On-Region Characteristics (Note E)



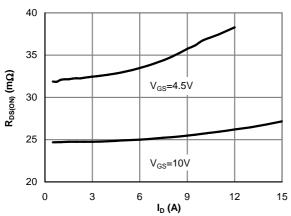


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

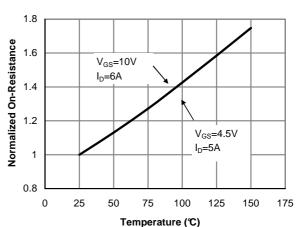


Figure 4: On-Resistance vs. Junction Temperature (Note E)

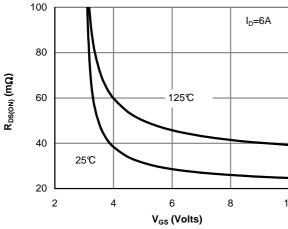


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

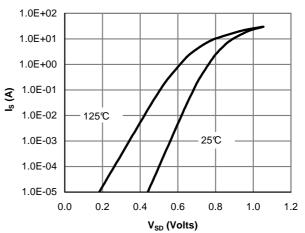
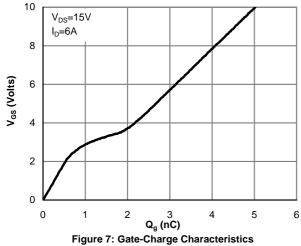


Figure 6: Body-Diode Characteristics (Note E)



400 350 300 Capacitance (pF) 250 200 150 100 50 C_{rss} 0 V_{DS} (Volts) 0 5 20 25 30

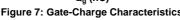
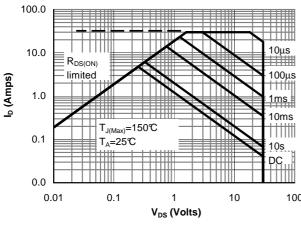


Figure 8: Capacitance Characteristics



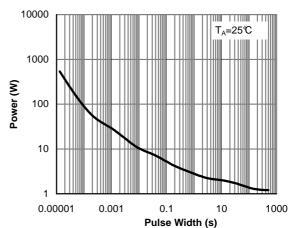


Figure 10: Maximum Forward Biased Safe Operating Area (Note F)

Figure 11: Single Pulse Power Rating Junction-to-Ambient (Note F)

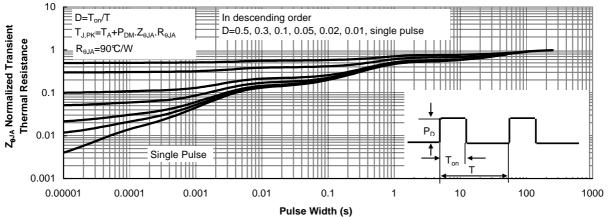
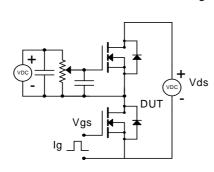
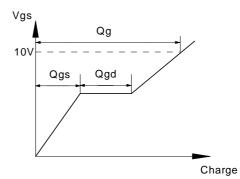


Figure 12: Normalized Maximum Transient Thermal Impedance (Note F)

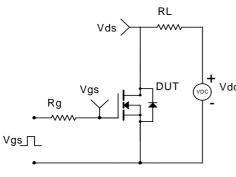


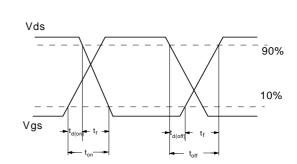
Gate Charge Test Circuit & Waveform



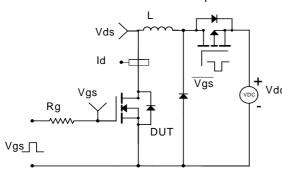


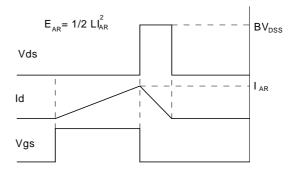
Resistive Switching Test Circuit & Waveforms



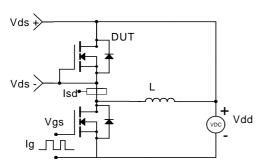


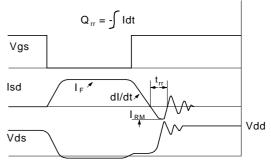
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





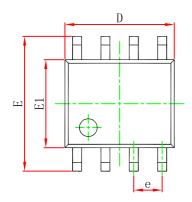
Diode Recovery Test Circuit & Waveforms

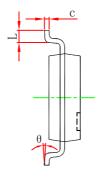


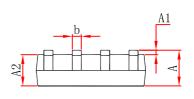




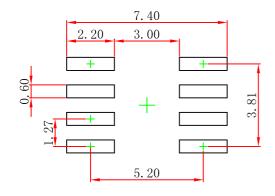
SOP-8(SOIC-8) Package Outline Dimensions







| Symbol | Dimensions In Millimeters | | Dimensions In Inches | | |
|----------|---------------------------|--------|----------------------|--------|--|
| 3y111001 | Min | Max | Min | Max | |
| A | 1. 350 | 1. 750 | 0.053 | 0.069 | |
| A1 | 0.100 | 0. 250 | 0.004 | 0.010 | |
| A2 | 1.350 | 1.550 | 0.053 | 0.061 | |
| b | 0.330 | 0.510 | 0.013 | 0.020 | |
| c | 0.170 | 0.250 | 0.007 | 0.010 | |
| D | 4.800 | 5.000 | 0.189 | 0. 197 | |
| e | 1.270 (BSC) | | 0.050 (BSC) | | |
| E | 5.800 | 6. 200 | 0. 228 | 0. 244 | |
| E1 | 3.800 | 4.000 | 0.150 | 0. 157 | |
| L | 0.400 | 1. 270 | 0.016 | 0.050 | |
| θ | 0° | 8° | 0° | 8° | |



Note:

- 1.Controlling dimension: in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

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